

**Notice of References Cited**

Application/Control No.

10/521,995

Applicant(s)/Patent Under  
Reexamination  
SEE ET AL.

Examiner

SHEELA C. CHAWAN

Art Unit

2624

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,730,495	03-1988	Green, Philip S.	73/620
	B	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.